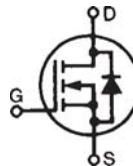


# HiPerFET™ Power MOSFET

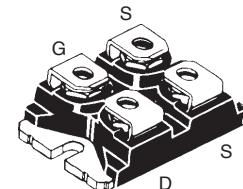
N-Channel Enhancement Mode  
Avalanche Rated, Low  $Q_g$ , Low Intrinsic  $R_g$   
High dV/dt, Low  $t_{rr}$

## IXFN66N50Q2

$V_{DSS} = 500$  V  
 $I_{D25} = 66$  A  
 $R_{DS(on)} = 80$  mΩ  
 $t_{rr} \leq 250$  ns



miniBLOC, SOT-227 B (IXFN)  
E153432



G = Gate                  D = Drain  
S = Source

Either Source terminal at miniBLOC can be used as Main or Kelvin Source

### Features

- Double metal process for low gate resistance
- miniBLOC, with Aluminium nitride isolation
- Unclamped Inductive Switching (UIS) rated
- Low package inductance
- Fast intrinsic Rectifier

### Applications

- DC-DC converters
- Switched-mode and resonant-mode power supplies
- DC choppers
- Pulse generators

### Advantages

- Easy to mount
- Space savings
- High power density

Symbol	Test Conditions	Maximum Ratings		
$V_{DSS}$	$T_j = 25^\circ\text{C}$ to $150^\circ\text{C}$	500		V
$V_{DGR}$	$T_j = 25^\circ\text{C}$ to $150^\circ\text{C}$ ; $R_{GS} = 1$ MΩ	500		V
$V_{GS}$	Continuous	±30		V
$V_{GSM}$	Transient	±40		V
$I_{D25}$	$T_c = 25^\circ\text{C}$	66		A
$I_{DM}$	$T_c = 25^\circ\text{C}$ , pulse width limited by $T_{JM}$	264		A
$I_{AR}$	$T_c = 25^\circ\text{C}$	66		A
$E_{AR}$	$T_c = 25^\circ\text{C}$	75		mJ
$E_{AS}$	$T_c = 25^\circ\text{C}$	4.0		J
$dv/dt$	$I_s \leq I_{DM}$ , $di/dt \leq 100$ A/μs, $V_{DD} \leq V_{DSS}$ $T_j \leq 150^\circ\text{C}$ , $R_G = 2$ Ω	20		V/ns
$P_D$	$T_c = 25^\circ\text{C}$	735		W
$T_J$		-55 ... +150		°C
$T_{JM}$		150		°C
$T_{stg}$		-55 ... +150		°C
$V_{ISOL}$	50/60 Hz, RMS, t = 1 minute	2500		V
$M_d$	Mounting torque Terminal connection torque	1.5/13	Nm/lb.in.	
		1.5/13	Nm/lb.in.	
Weight		30		g

Symbol	Test Conditions	Characteristic Values		
		( $T_j = 25^\circ\text{C}$ , unless otherwise specified)	min.	typ.
$V_{DSS}$	$V_{GS} = 0$ V, $I_D = 3$ mA	500		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$ , $I_D = 8$ mA	2.0		4.5 V
$I_{GSS}$	$V_{GS} = \pm 30$ V, $V_{DS} = 0$			±200 nA
$I_{DSS}$	$V_{DS} = V_{DSS}$ $V_{GS} = 0$ V	$T_j = 25^\circ\text{C}$ $T_j = 125^\circ\text{C}$		50 μA 3 mA
$R_{DS(on)}$	$V_{GS} = 10$ V, $I_D = 0.5 \bar{I}_{D25}$			80 mΩ

Symbol	Test Conditions	Characteristic Values		
		min.	typ.	max.
$g_{fs}$	$V_{DS} = 10 \text{ V}; I_D = 0.5 \text{ } I_{D25}$ Note 1	30	44	S
$C_{iss}$ $C_{oss}$ $C_{rss}$	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$	6800		pF
		1200		pF
		270		pF
$t_{d(on)}$ $t_r$ $t_{d(off)}$ $t_f$	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \text{ } V_{DSS}, I_D = 0.5 \text{ } I_{D25}$ $R_G = 1 \Omega$ (External)	32		ns
		16		ns
		60		ns
		12		ns
$Q_{G(on)}$ $Q_{GS}$ $Q_{GD}$	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \text{ } V_{DSS}, I_D = 0.5 \text{ } I_{D25}$	199		nC
		42		nC
		92		nC
$R_{thJC}$			0.17	K/W
$R_{thCK}$		0.05		K/W

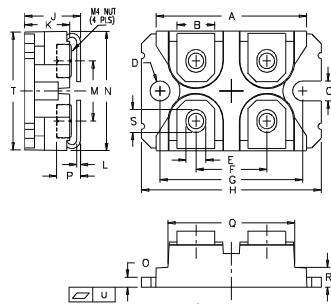
## Source-Drain Diode

Characteristic Values  
( $T_J = 25^\circ\text{C}$ , unless otherwise specified)

Symbol	Test Conditions	min.	typ.	max.
$I_s$	$V_{GS} = 0 \text{ V}$		66	A
$I_{SM}$	Repetitive; pulse width limited by $T_{JM}$		264	A
$V_{SD}$	$I_F = I_s, V_{GS} = 0 \text{ V}$ , Note 1		1.5	V
$t_{rr}$ $Q_{RM}$ $I_{RM}$	$I_F = 25 \text{ A}$ $-di/dt = 100 \text{ A}/\mu\text{s}$ $V_R = 100 \text{ V}$		250	ns
		1.0		$\mu\text{C}$
		10		A

Note: 1. Pulse test,  $t \leq 300 \mu\text{s}$ , duty cycle  $d \leq 2 \%$ 

## minibLOC, SOT-227 B Outline



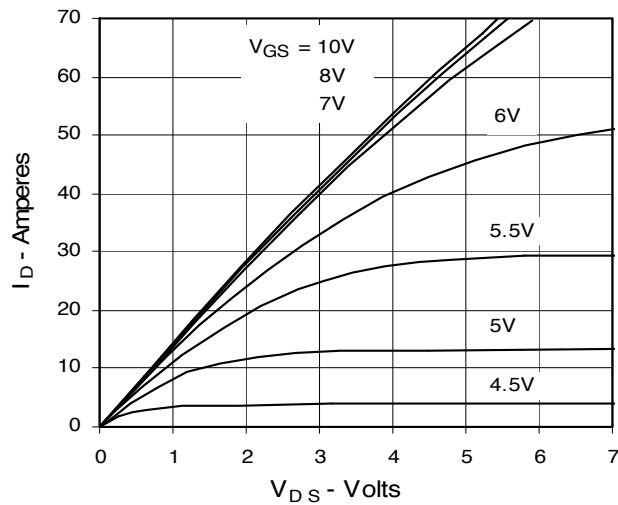
M4 screws (4x) supplied

Dim.	Millimeter		Inches	
	Min.	Max.	Min.	Max.
A	31.50	31.88	1.240	1.255
B	7.80	8.20	0.307	0.323
C	4.09	4.29	0.161	0.169
D	4.09	4.29	0.161	0.169
E	4.09	4.29	0.161	0.169
F	14.91	15.11	0.587	0.595
G	30.12	30.30	1.186	1.193
H	38.00	38.23	1.496	1.505
J	11.68	12.22	0.460	0.481
K	8.92	9.60	0.351	0.378
L	0.76	0.84	0.030	0.033
M	12.60	12.85	0.496	0.506
N	25.15	25.42	0.990	1.001
O	1.98	2.13	0.078	0.084
P	4.95	5.97	0.195	0.235
Q	26.54	26.90	1.045	1.059
R	3.94	4.42	0.155	0.174
S	4.72	4.85	0.186	0.191
T	24.59	25.07	0.968	0.987
U	-0.05	0.1	-0.002	0.004

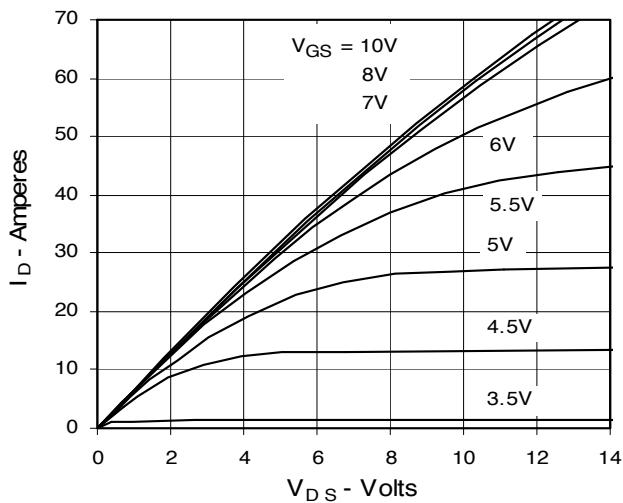
IXYS reserves the right to change limits, test conditions, and dimensions.

IXYS MOSFETs and IGBTs are covered by 4,835,592 4,931,844 5,049,961 5,237,481 6,162,665 6,404,065 B1 6,683,344 6,727,585 one or more of the following U.S. patents: 4,850,072 5,017,508 5,063,307 5,381,025 6,259,123 B1 6,534,343 6,710,405 B2 6,759,692 4,881,106 5,034,796 5,187,117 5,486,715 6,306,728 B1 6,583,505 6,710,463 6,771,478 B2

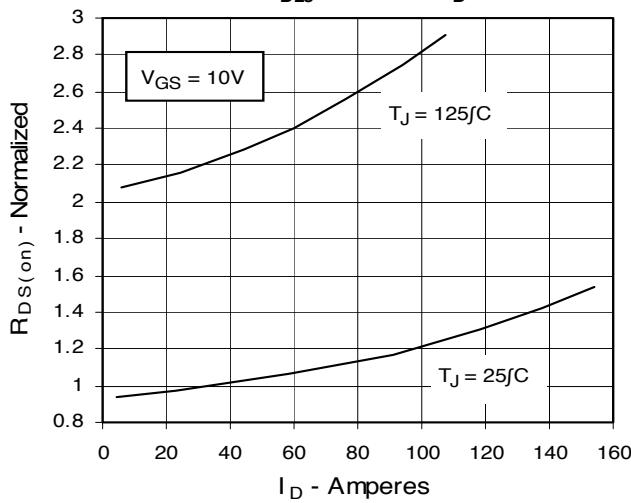
**Fig. 1. Output Characteristics  
@ 25°C**



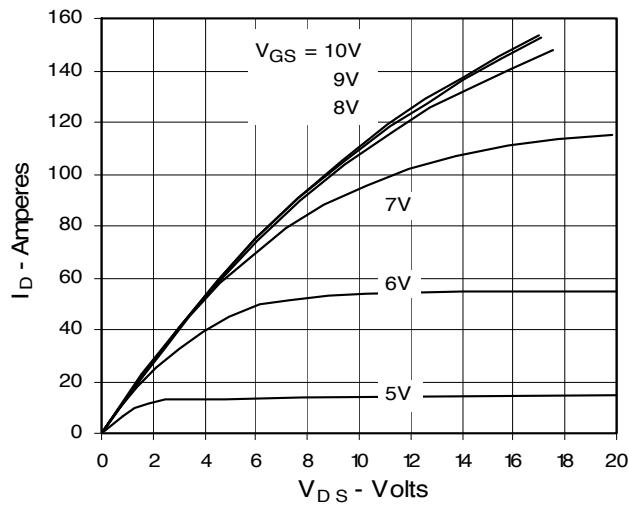
**Fig. 3. Output Characteristics  
@ 125°C**



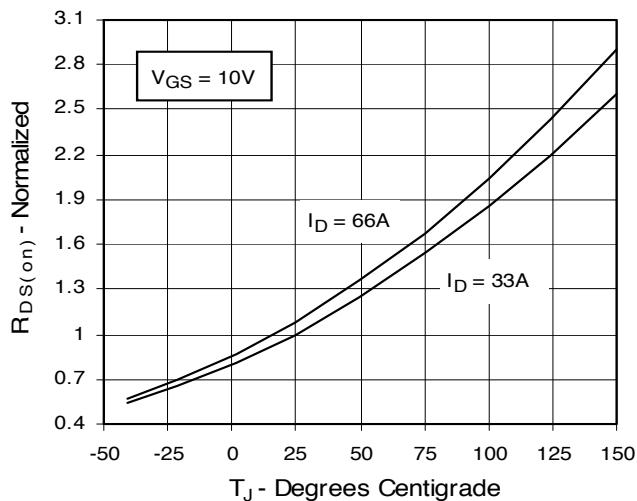
**Fig. 5.  $R_{DS(on)}$  Normalized to  
0.5  $I_{D25}$  Value vs.  $I_D$**



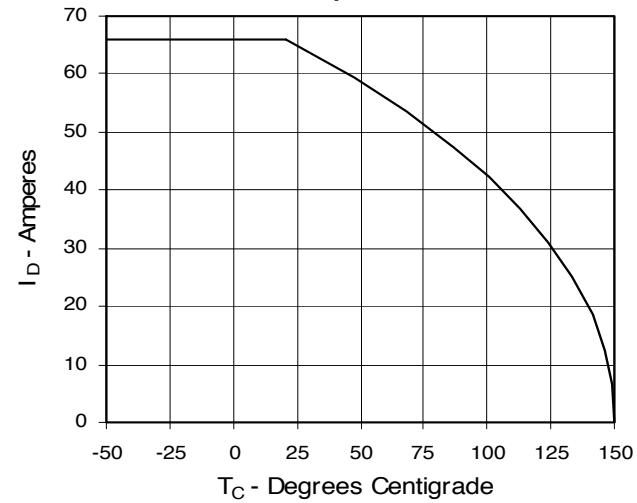
**Fig. 2. Extended Output Characteristics  
@ 25°C**

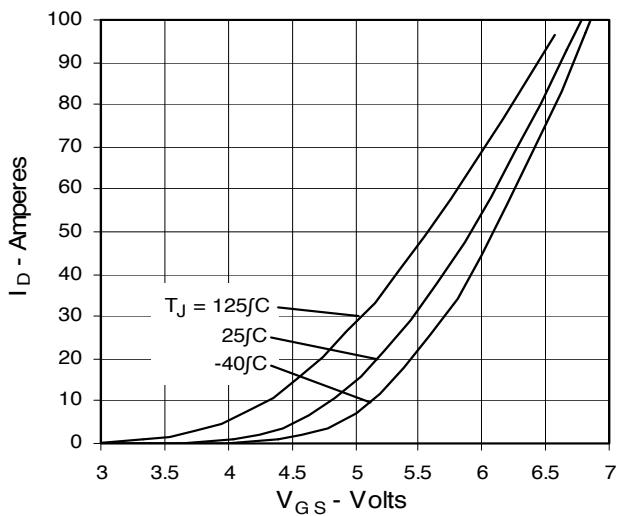
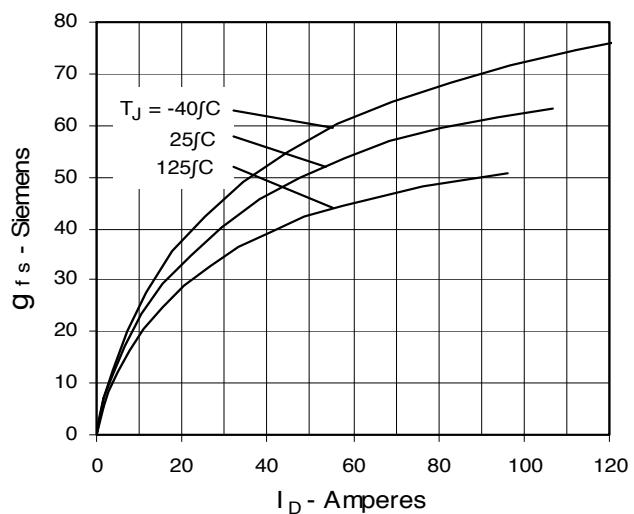
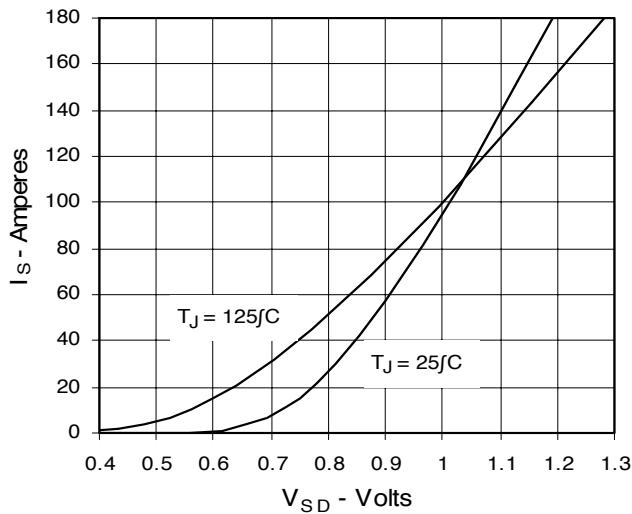
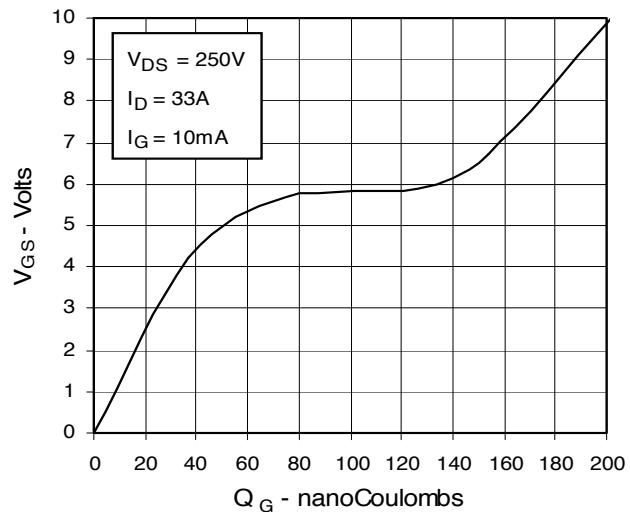
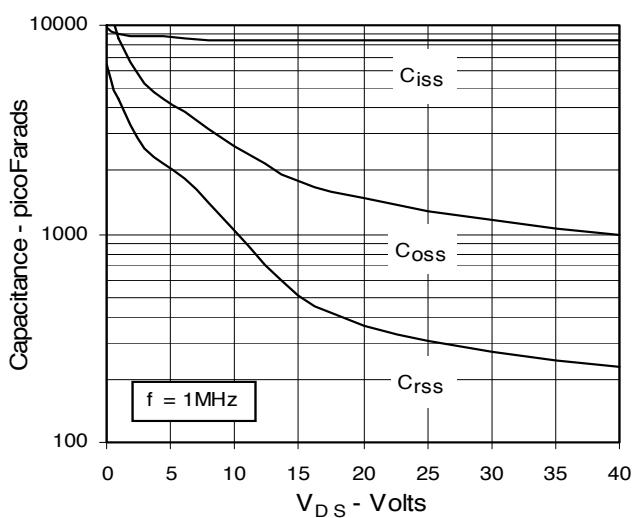
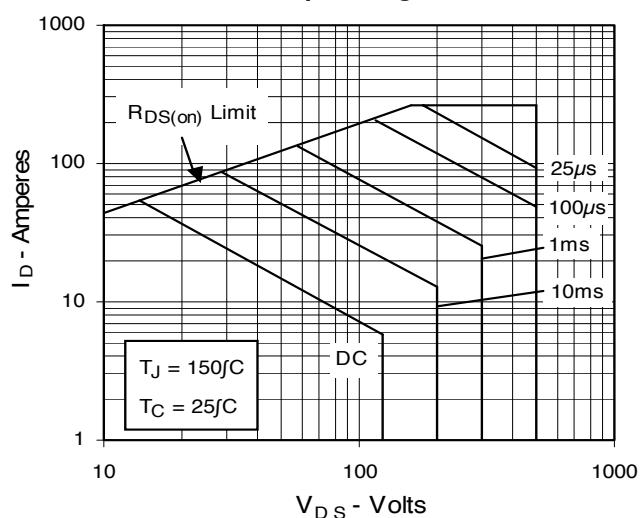


**Fig. 4.  $R_{DS(on)}$  Normalized to 0.5  $I_{D25}$   
Value vs. Junction Temperature**



**Fig. 6. Drain Current vs. Case  
Temperature**



**Fig. 7. Input Admittance**

**Fig. 8. Transconductance**

**Fig. 9. Source Current vs. Source-To-Drain Voltage**

**Fig. 10. Gate Charge**

**Fig. 11. Capacitance**

**Fig. 12. Forward-Bias Safe Operating Area**


**Fig. 13. Maximum Transient Thermal Resistance**